

Electron density calculation and structural analysis of $\text{Li}_{0.5}\text{Bi}_{0.5}\text{TiO}_3$ ceramic

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ABSTRACT

$\text{Li}_{0.5}\text{Bi}_{0.5}\text{TiO}_3$ ceramic powder was synthesized by high energy ball milling. The X-ray diffraction pattern of the sample was analyzed in a quantitative manner using rietveld analysis. X-rays is the finger print of a material and the diffracted intensity can be used to dig out a lot of information related to the material. Again to tailored a material it is necessary to understand the geometry of a material in a quantifying manner. So, in this study it is tried to present a indepth study of the material in term of its atomic positions, bond lengths, bond angles and energy density of different levels. Lastly, a simulated structure is presented using all the initial data available and its energy density.

Keywords: X-ray diffraction; Electron density; Rietveld refinement

INTRODUCTION

Lead oxide based ferroelectrics, represented by lead zirconate titanate $\text{Pb}(\text{Zr}, \text{Ti})\text{O}_3$, (PZT) are widely used for piezoelectric actuators, sensors and transducers due to their excellent piezoelectric properties [1-2]. However, lead is a heavy metal and its toxicity is well known. Therefore, it is necessary to develop lead-free piezoelectric ceramics to replace PZT based ceramics. Sodium bismuth titanate ($\text{Na}_{0.5}\text{Bi}_{0.5}\text{TiO}_3$, NBT), discovered by Smolenskii et al. in 1960 [3], is considered to be one of the candidates of lead-free piezoelectric ceramics. However, NBT has a drawback of high conductivity and high coercive field which cause problems in polarizing process [4]. Thus in the same light $\text{Li}_{0.5}\text{Bi}_{0.5}\text{TiO}_3$ ceramic is synthesized using high energy mechanosynthesis. Though this material have been reported some time as a single or in composite form for different applications, its detailed structure is not reported with clarity. In this paper it is tried to present a thorough and detailed structural analysis of the material from x-ray diffraction. A geometrical structure along with its energy density for different levels is also presented.

MATERIALS AND METHODS

In the present study commercial ceramic powders of Bi_2O_3 (99 wt%), TiO_2 (99 wt%), and Li_2CO_3 (97 wt%) were used as the raw materials. A powder mixture of these raw materials according to the stoichiometric ratio of $\text{Bi}_{0.5}\text{Li}_{0.5}\text{TiO}_3$ was prepared. The prepared reactant was ball milled for 3 hours in a zirconia vial using 40 zirconia balls at a speed of 300 rpm in an ethanol medium. After ball milling, the obtained slurry was dried at 80 °C for 6 h to remove the ethanol. The products were then grounded in an agate mortar for 1/2 hour. The processed ceramic powder were then structurally characterized by a PANalytical X'pert-MPD X-ray diffractometer (XRD). The XRD data were recorded using Ni-filtered Cu K_α radiation from a highly-stabilized and automated Philips X-ray generator (PW 1830) operated at 30 kV and 20 mA. The generator is coupled with a Philips X-ray powder diffractometer consisting of a PW 3040 mpd controller, PW 1050/51 goniometer of radius 240 mm, and a proportional counter with 1° divergence slit, and 1 mm receiving slit. The step-scan data of step size 0.017° and step scan 0.6 s were recorded for the entire angular range 10–90°.

Theory:

Microstructure characterization of the ball-milled powder samples has been made by employing the Rietveld's whole-profile fitting method based on structure and microstructure refinement [5-6]. The experimental profiles were fitted with the most suitable pseudo-Voigt analytical function because it takes individual care for both the particle size and strain broadening of the experimental profiles. For both the K_{a1} and K_{a2} profiles, the line broadening function $B(2\theta)$ and the symmetric part of instrumental function $S(2\theta)$ may be represented by the pseudo-Voigt function

$$pV(x) = \sum I_{nt} [\eta C(x) + (1 - \eta)G(x)] \quad (1)$$

where the Cauchyian component, $C(x) = (1 + x^2)^{-1}$ and the Gaussian component, $G(x) = \exp[-(\ln 2)x^2]$. The powder diffraction patterns were simulated providing all necessary structural information and some starting values of microstructural parameters of the individual phases with the help of the Rietveld software, Fullprof [7-8].

Initially, the positions of the peaks were corrected by successive refinements of zero-shift error. Considering the integrated intensity of the peaks as a function of structural parameters only, the Marquardt least-squares procedures were adopted for minimization of the difference between the observed and simulated powder diffraction patterns and the minimization was carried out by using the reliability index parameter, R_{wp} (weighted residual error), R_{exp} (expected error) and R_B (Bragg factor) defined as:

$$R_{wp} = \left[\frac{\sum w_i (I_0 - I_c)^2}{\sum w_i I_0^2} \right]^{1/2} \quad (2)$$

$$R_B = 100 \frac{\sum |I_0 - I_c|}{\sum I_0} \quad (3)$$

and

$$R_{exp} = \left| \frac{N - P}{\sum w_i I_0^2} \right|^{1/2} \quad (4)$$

where I_0 and I_c are the experimental and calculated intensities, respectively, w_i ($1/I_0$) and N are the weight and number of experimental observations, and P is the number of fitting parameters.

The goodness of fit (GoF) is established by comparing R_{wp} with the expected error, R_{exp} . This leads to the value of goodness of fit [9-10]:

$$GOF = \frac{R_{wp}}{R_{exp}} \quad (5)$$

Refinement continues till convergence is reached

RESULTS AND DISCUSSION

In the present study rietveld profile matching and integrated intensity refinement analysis of X-ray of powder diffraction data is adopted to obtain the refined structural parameters, such as atomic coordinates, occupancies, lattice parameters, microstructural parameters, and energy density using Fullprof version 2.50 Rietveld software. The XRD pattern of LBT ceramic is shown in fig.1. The refinements were conducted without refining the isotropic atomic thermal parameters.

The x-ray pattern shows 3 different major phases, namely, lithium bismuth phosphorous (V) oxide as 68.8%, lithium dioxobismuthate as 29.8% and dilithium tetrabismuth dititanium(III) titanium oxide as 1.4%. matched with with JCPDS data card #(98-001-4563), (98-000-8950) and (98-006-4716) respectively. During refinement process the different structural parameters obtained are enlisted here as, Tip Width, 3.79473 Å, Obs. Lorentz B [$^{\circ}2\theta$]=6.01522, Obs. Gauss B [$^{\circ}2\theta$]=0.10206, Obs. B [$^{\circ}2\theta$]=6.04358, Instr. Lorentz B [$^{\circ}2\theta$]=0.07470, Instr. Gauss B [$^{\circ}2\theta$]=0.06328, Instr. B [$^{\circ}2\theta$]=0.11842, Struct. Lorentz B [$^{\circ}2\theta$]=5.94052, Struct. Gauss B [$^{\circ}2\theta$]=0.08008, Struct. B [$^{\circ}2\theta$]=5.94160, Universal Shape=0.52325, Micro Strain [%]=0.16447, Crystallite Size [\AA]=15.19054. Different structure factor are estimated to be, F observed=170.1585, F calculated=141.3984 and F esd=15.21149 with multiplicity 8.

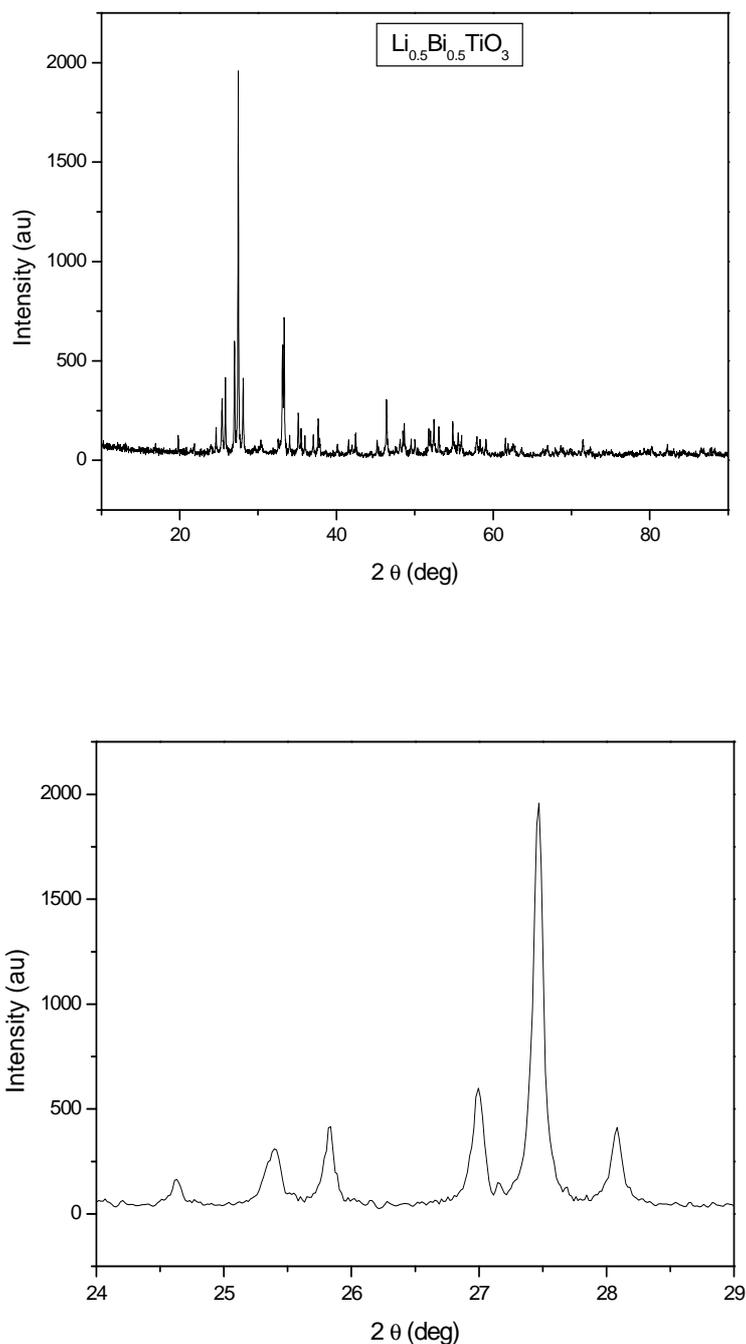


Fig.1 : X-ray Diffraction of $\text{Li}_{0.5}\text{Bi}_{0.5}\text{TiO}_3$ ceramic

Different refined parameters are calculated to be , $R_p=37.5410$, $R_{wp}=44.7160$, $R_{exp}=15.9455$ with $GOF = 7.8641$. The Caglioti width is estimated to be $U=10$ (2.8066), $V=-1$ (2.3498) and $W=2.1634$ (0.4496).

After refinement a crystal structure with the following data was obtained. crystal system: orthorhombic, space group= $I b a m$ and space group no.=72. The lattice parameters (\AA) are found to be, $a=5.1034$ (0.01145), $b=17.9131$ (0.03145) and $c=4.8308$ (0.0096) with $\alpha=\beta=\gamma=90^\circ$. Table-1 shows the x-ray diffraction data of $\text{Li}_{0.5}\text{Bi}_{0.5}\text{TiO}_3$ ceramic with inter-planer spacing, crystallite size and (h k l) parameters of individual planes. FWHM and intensity(cts) is also mentioned for the individual planes. The energy density and generated structure from analysis seems to be very interesting with different level of energy. The energy density (ED) from Fourier analysis is given in the **table-2**.

Table-1: X-ray diffraction data of $\text{Li}_{0.5}\text{Bi}_{0.5}\text{TiO}_3$ ceramic

Sl. No.	(2 θ)	h	k	d (nm)	FWHM	Cts	D (nm)
1	19.80	1/2	0	0.4481	0.1224	62.97	64.65
2	24.63	1/2	1	0.3611	0.0816	127.05	100.38
3	25.40	2/2	0	0.3504	0.1632	265.45	50.51
4	25.86	2/0	2	0.3442	0.0612	384.63	135.20
5	27.02	2/2	1	0.3297	0.102	1934.35	81.94
6	27.46	3/0	0	0.3246	0.0612	576.35	137.11
7	28.04	1/0	0	0.3180	0.0816	378.99	103.38

8	30.33	3/1	1	0.2945	0.3264	57.83	26.43
9	33.15	3/0	2	0.2701	0.0816	548.74	108.98
10	34.08	3/2	1	0.2628	0.1224	89.08	73.45
11	35.55	0/4	0	0.2523	0.1224	93.76	74.77
12	36.90	4/0	0	0.2434	0.1224	99.98	76.06
13	37.75	3/2	2	0.2381	0.1224	160.01	76.94
14	40.22	2/4	0	0.2403	0.2448	43.30	39.83

Table-2: Energy Density

No.	ED
1	18.719
2	18.631
3	16.831
4	16.438
5	13.505
6	13.505
7	12.015
8	11.979
9	11.597
10	11.597

11	11.565
12	11.501
13	9.999
14	9.908
15	9.889
16	9.889
17	9.717
18	9.564
19	9.080
20	9.080
21	8.861

22	8.666
23	8.665
24	8.665
25	8.665
26	8.156
27	7.848
28	7.848
29	7.650
30	7.650
31	7.423
32	7.398

33	7.398
34	7.140
35	7.139
36	7.102
37	7.102
38	6.997
39	6.997
40	6.992
41	-10.360
42	-10.360
43	-9.863

44	-9.863
45	-8.434
46	-8.145
47	-8.039
48	-7.931

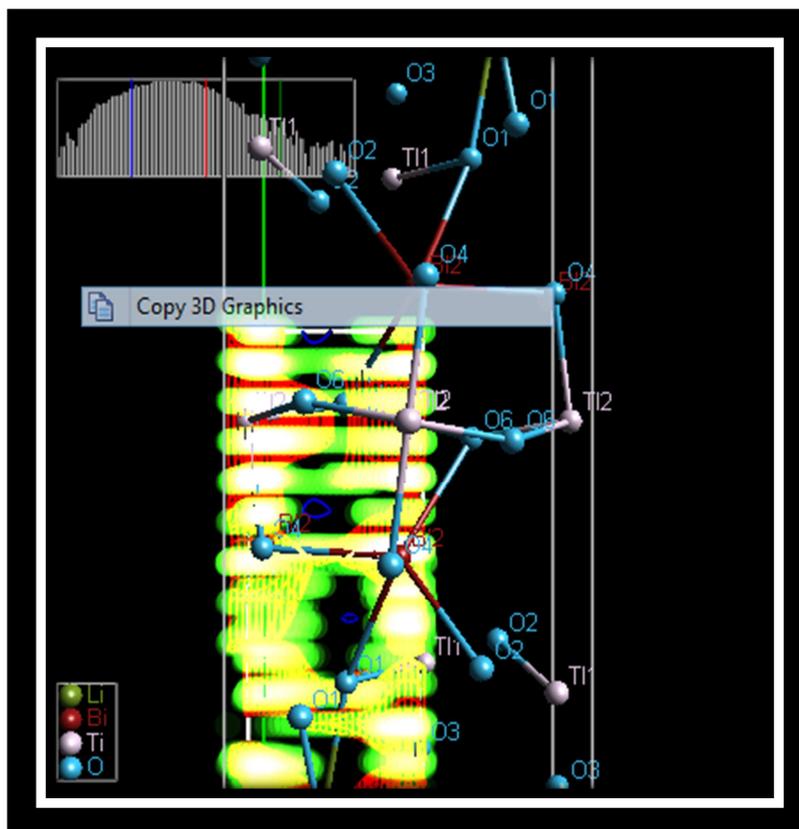


Fig.2 schematic representation of Electron density and structure from Fourier analysis

possible bond angles and bond lengths between the different Li, Bi, Ti and O- atoms. This gives a clear picture of the material with proper understanding for tailoring the material.

CONCLUSION

A comprehensive structural analysis is done on the basis of X-ray diffraction of the LBT ceramics in terms of its bond lengths, bond angles and the atomic positions of the different atoms. A simulated probable structure is also presented in the study. Above all the energy density of all the atoms at different levels are also presented. By understanding the crystal structure of a material it is always wise to tailored the material as per requirement of technology and situation. This study really gives an insight to the structure of the material.

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